

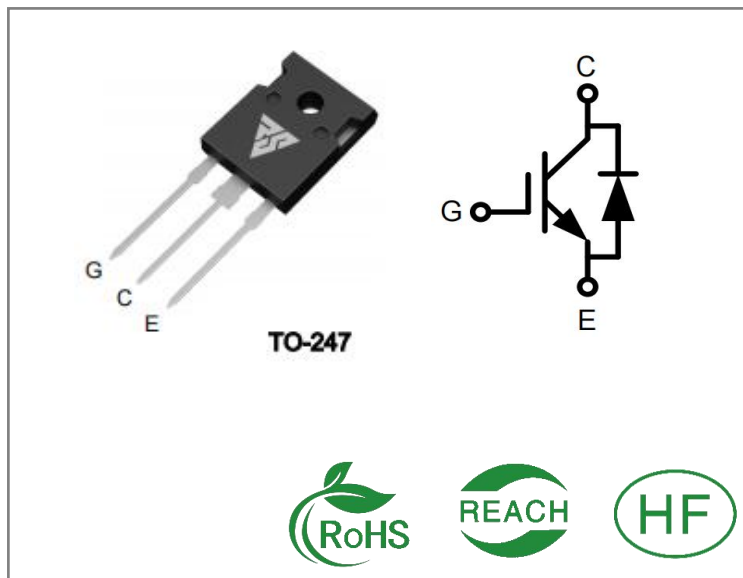
IF	V _{ce(sat)}	VCES
75A	1.56V	650V

Applications:

- EV Charging
- Uninterruptible Power Supply (UPS)
- Solar converters

Features:

- 650V trench gate/field termination process
- Very low V_{ce(sat)}
- Low switching loss
- Positive temperature coefficient in V_{ce(sat)}


Ordering Information

Part Number	Package	Marking	Packing	Qty.
RSG75N65UW	T0-247-3	RSG75N65UW	Tube	30 PCS

Absolute Maximum Ratings T_c= 25°C unless otherwise specified

Symbol	Parameter	RSG75N65UW	Units
VCES	Collector-Emitter Voltage	650	V
VGES	Gate- Emitter Voltage	±20	V
IC	Continuous DC collector current TC = 100 °C	75	A
ICrm	Repetitive peak collector current tp=1 ms	300	A
Ptot	Total Power Dissipation @ TC = 25°C	520	W
Tstg	Operating Junction and Storage Temperature Range	-40to150	°C
TL	Maximum Temperature for Soldering	260	°C

Thermal Characteristic

Symbol	Parameter	RSG75N65UW	Units
R _{thJC}	Thermal Resistance, Junction to case for IGBT	0.29	K/ W

Electrical Characteristics ($T_c=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions	
Static Characteristics							
V(BR)CES	Collector-Emitter Breakdown Voltage	650	-	--	V	V _{GE} =0V,I _{CE} =1mA	
ICES	Collector-Emitter Leakage Current	-	-	1	mA	V _{GE} =0V, V _{CE} =650V	
IGES	Gate to Emitter Leakage current	-	-	200	nA	V _{GE} =+20V, V _{CE} =0V	
VCE(sat)	Collector-Emitter Saturation Voltage	-	1.56	2	V	I _C =75A V _{GE} =15V	T _j =25° C
	Gate Threshold Voltage	-	1.9	--	V	V	T _j =175° C
VGE(th)	Collector-Emitter Breakdown Voltage	3.8	4.4	5.0	V	I _C =0.75mA,V _{CE} =V _{GE}	
Gfs	Transconductance		58		S	I _C =75A,V _{CE} =20V	
Dynamic Characteristics							
Cies	Input Capacitance	-	4470	--	PF	V _{CE} =25V, V _{GE} =0V, f=100KHz	
Coes	Output Capacitance	-	170	--			
Cres	Reverse Transfer Capacitance	-	21	--			
Qg	Total Gate Charge		273		nC	IC = 75 A, VGE = 15 V, VCE =520 V	
Switching Characteristics							
td(ON)	Turn-on Delay Time	-	25		ns	V _{CE} =300V, I _C =75A, V _{GE} =+/-15V, R _g =8Ω, Inductive Load	
t _r	Rise Time	-	130	--			
td(OFF)	Turn-Off Delay Time	-	81	--			
t _f	Fall Time	-	56				
E _{on}	Turn-On Switching Loss	-	2.65	--	mJ		
E _{off}	Turn-Off Switching Loss	-	1.02	--			

Diode Maximum Ratings (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions
VRRM	Repetitive Peak Reverse Voltage	650	V	TC = 25°C
IF	Forward Current	75	A	TC = 100°C
IFRM	Repetitive Peak Forward Surge Current	300	A	tp=1 ms

Characteristics Values (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Min.	Typ.	Max.	Test Conditions	Unit
VF	Forward Voltage		1.55 1.69 1.70	2.0	IF = 75A, V _{GE} = 0V T _J = 25°C IF = 75A, V _{GE} = 0V T _J = 150°C IF = 75A, V _{GE} = 0V T _J = 175°C	V
IRM	Peak reverse recovery current		16 26		VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 25°C VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 175°C	A
Qrr	Reverse Recovery Charge		1.28 3.18		VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 25°C VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 175°C	μC
trr	Reverse Recovery time		155 225		VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 25°C VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 175°C	ns
Erec	Reverse recovered energy		0.19 0.54		VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 25°C VR = 300V, IF = 75A, V _{GE} = -15V diF/dt = 500A/μs T _J = 175°C	mJ
R _{thJC}	Diode Thermal Resistance, Junction		0.35			K/ W
Tvj op	Temperature under switching conditions	-40		175		°C

Typical Feature Curve

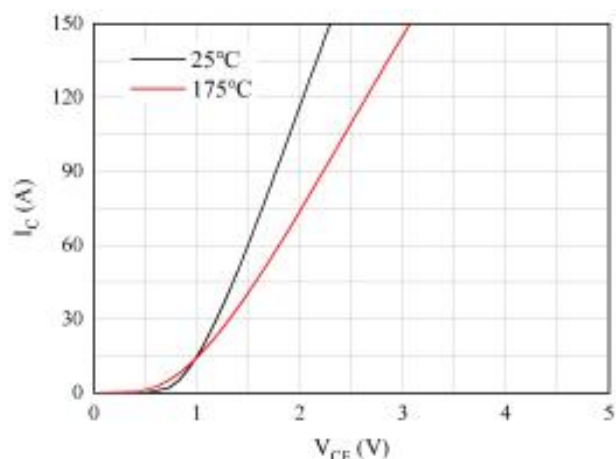


图 1. 典型输出特性 ($V_{GE}=15V$)

Figure 1. Typical output characteristics ($V_{GE}=15V$)

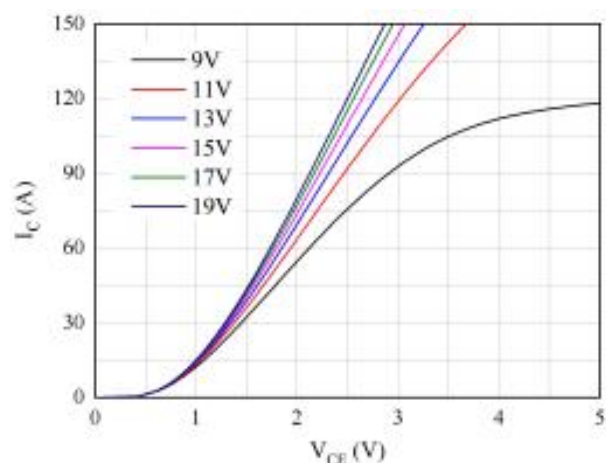


图 2. 典型输出特性 ($T_V=175^{\circ}C$)

Figure 2. Typical output characteristics ($T_V=175^{\circ}C$)

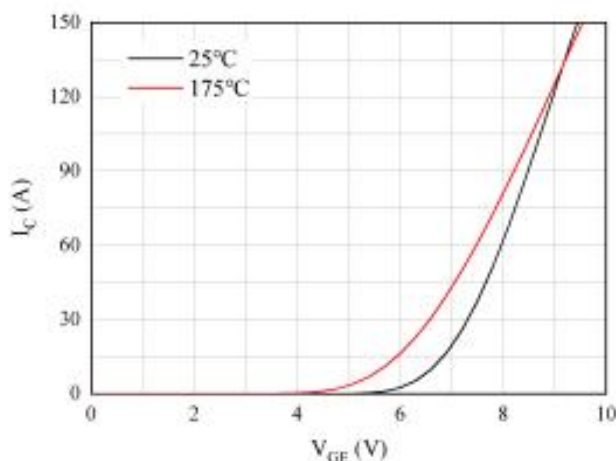


图 3. 典型传输特性 ($V_{CE}=20V$)

Figure 3. Typical transfer characteristic ($V_{CE}=20V$)

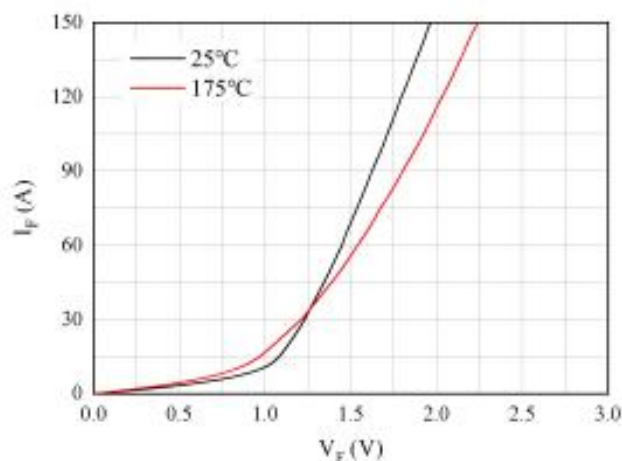


图 4. 正向偏压特性 二极管

Figure 4. Forward characteristic of Diode

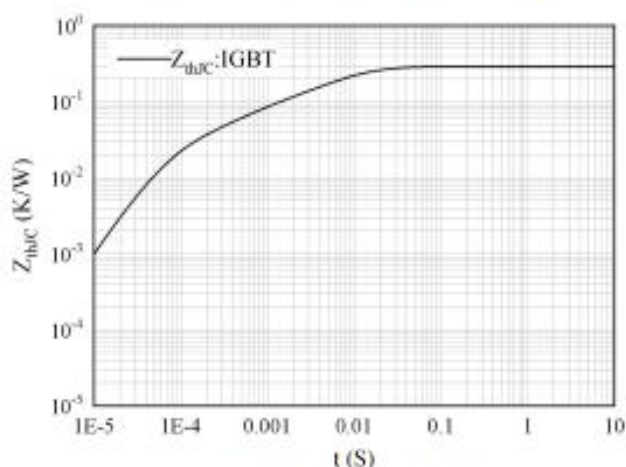


图 5. 瞬态热阻抗 IGBT

Figure 5. Transient thermal impedance IGBT,
 $Z_{thJC}=f(t)$

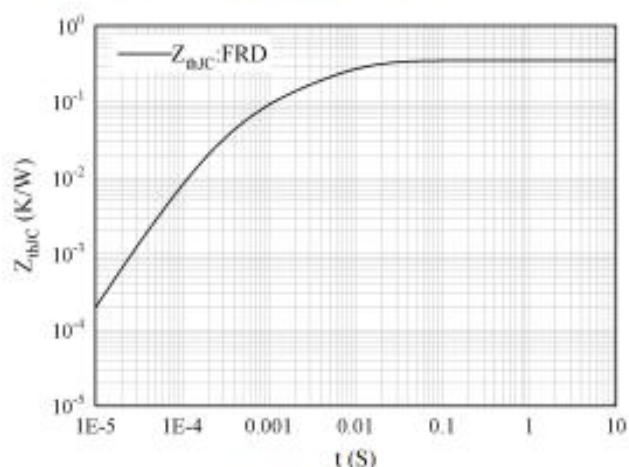


图 6. 瞬态热阻抗 FRD

Figure 6. Transient thermal impedance FRD,
 $Z_{thJC}=f(t)$

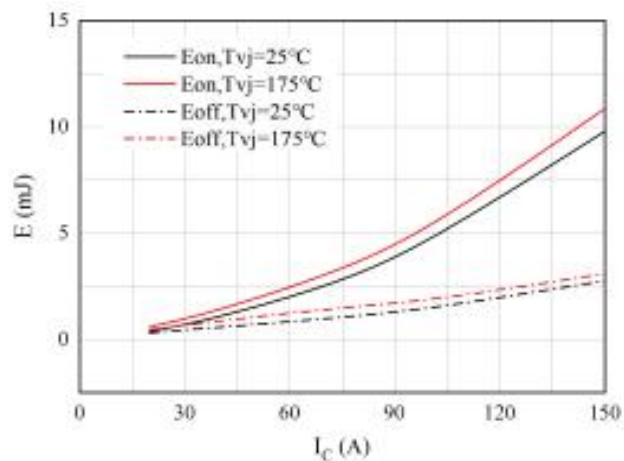


图 7. 开关损耗

Figure 7. Switching losses of IGBT
 $V_{GE} = \pm 15V$, $R_{gon} = 8\Omega$, $R_{goff} = 8\Omega$, $V_{CE} = 300V$

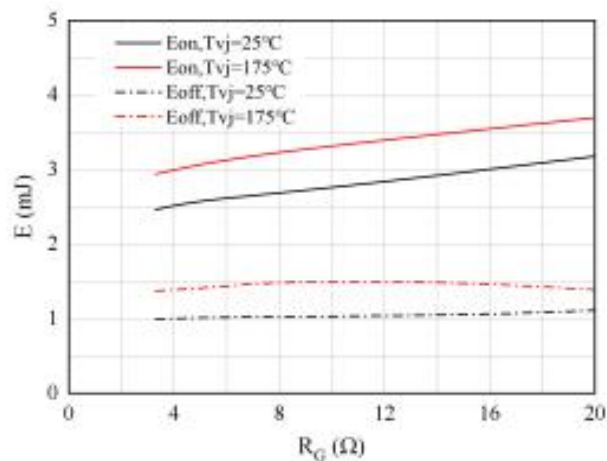


图 8. 开关损耗

Figure 8. Switching losses of IGBT
 $V_{GE} = \pm 15V$, $I_C = 75A$, $V_{CE} = 300V$

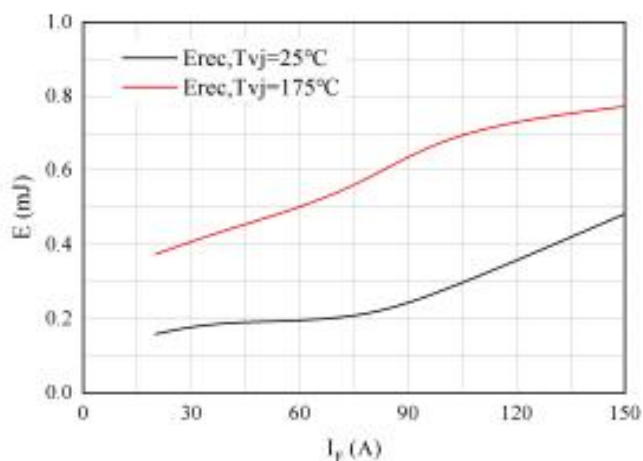


图 9. 开关损耗 二极管

Figure 9. Switching losses of Diode
 $R_{gon} = 8\Omega$, $V_{CE} = 300V$

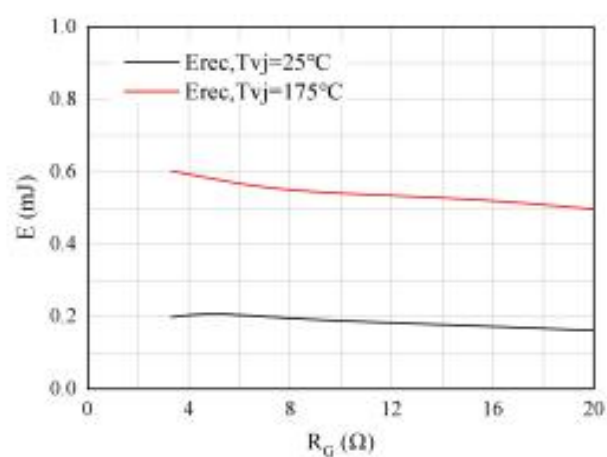


图 10. 开关损耗 二极管

Figure 10. Switching losses of Diode
 $I_F = 75A$, $V_{CE} = 300V$

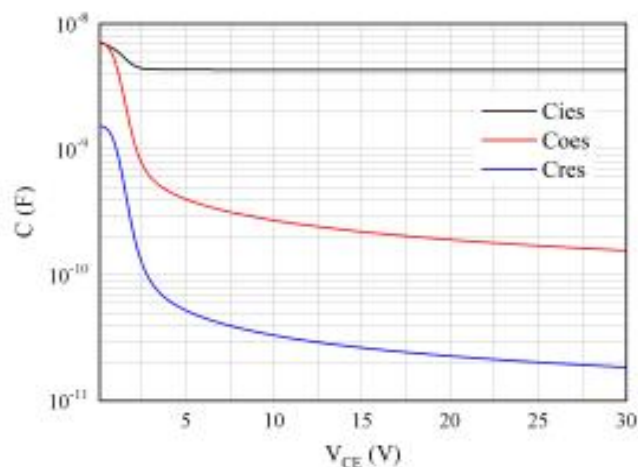
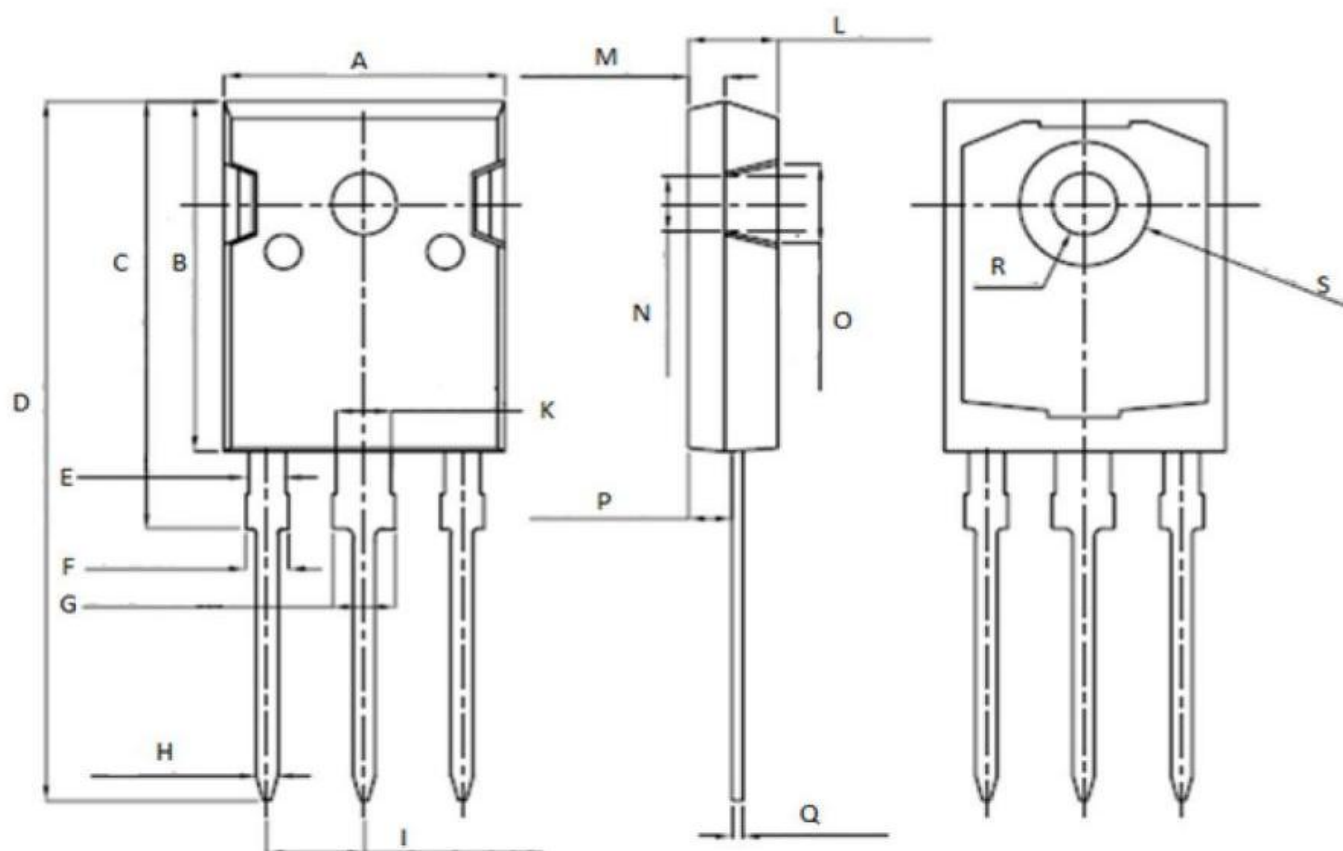


图 11. 电容特性

Figure 11. Capacitance characteristic

Package outline drawing(TO-247-3 Unit: mm)



Unit: mm		
Symbol	Min.	Max.
A	15.95	16.25
B	20.85	21.25
C	20.95	21.35
D	40.5	40.9
E	1.9	2.1
F	2.1	2.25
G	3.1	3.25
H	1.1	1.3
I	5.40	5.50

Unit: mm		
Symbol	Min.	Max.
K	2.90	3.10
L	4.90	5.30
M	1.90	2.10
N	4.50	4.70
O	5.40	5.60
P	2.29	2.49
Q	0.51	0.71
R	φ 3.5	φ 3.7
S	φ 7.1	φ 7.3

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